



DOCUMENT CHANGE REQUEST

DCR number 995 Changes required for: General

Originator: Steve Thacker

Date: 2016/12/07

Date sent: 2016/05/12

Organisation: ESCC Executive Secretariat

Status: IMPLEMENTED

Title: Matched Dual Transistors NPN, based on types 2N2919/2N2920 and 2N2920A

Number: 5207/002

Issue: 6

Other documents affected:

Page:

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Paragraph:

2.4.1 Room Temperature Electrical Measurements

Original wording:

See 5207/002 issue 5

Proposed wording:

For characteristic: Base-Emitter Voltage Differential 1 & 2, correct the IC test conditions as follows:

For $|V_{BE1}-V_{BE2}|_1$: IC = 10uA (not 10mA)

For $|V_{BE1}-V_{BE2}|_2$: IC = 100uA (not 100mA)

Justification:

typographic error in previous issue

Attachments:

N/A

Modifications:

N/A

Approval signature:

Date signed:

2016-12-07